

DESCRIPTION

The 82S230 and 82S231 include on-chip decoding and 1 chip enable input for ease of memory expansion. They feature either open collector or tri-state outputs for optimization of word expansion in bused organizations.

Both 82S230 and 82S231 devices are available in the commercial and military temperature ranges. For the commercial temperature range (0°C to +75°C) specify N82S230/231, F or N, and for the military temperature range (-55°C to +125°C) specify S82S230/231, F.

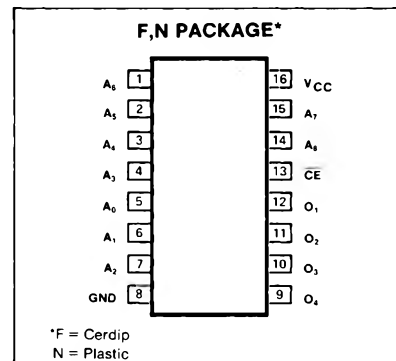
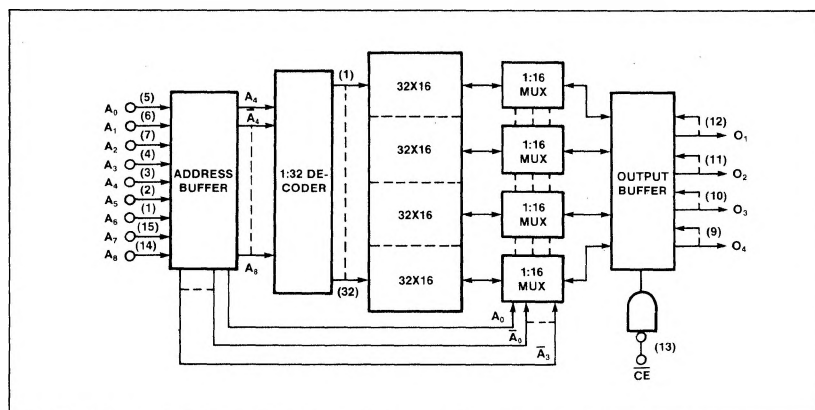
FEATURES

- Address access time:
N82S230/231: 50ns max
S82S230/231: 70ns max

- Power dissipation: 0.3mW/bit typ
- Input loading:
N82S230/231: -100 μ A max
S82S230/231: -150 μ A max
- On-chip address decoding
- Output options:
82S230: Open collector
82S231: Tri-state
- Fully compatible with Signetics 82S130/131 PROMs
- Fully TTL compatible

APPLICATIONS

- Sequential controllers
- Microprogramming
- Hardwired algorithms
- Control store
- Random logic
- Code conversion

PIN CONFIGURATION**BLOCK DIAGRAM****ABSOLUTE MAXIMUM RATINGS**

PARAMETER	RATING	UNIT
V _{CC} Supply voltage	+7	Vdc
V _{IN} Input voltage	+5.5	Vdc
V _{OH} Output voltage		Vdc
High (82S230)	+5.5	
V _O Off-state (82S231)	+5.5	
Temperature range		°C
T _A Operating	0 to +75	
N82S230/231	-55 to +125	
S82S230/231	-65 to +150	
T _{STG} Storage		

DC ELECTRICAL CHARACTERISTICS N82S230/231: $0^{\circ}\text{C} \leq T_A \leq +75^{\circ}\text{C}$, $4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$
 S82S230/231: $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$

PARAMETER	TEST CONDITIONS ¹	N82S230/231			S82S230/231			UNIT
		Min	Typ ²	Max	Min	Typ ²	Max	
V_{IL} Input voltage Low V_{IH} High V_{IC} Clamp	$I_{IN} = -18\text{mA}$	2.0	-0.8	.85 -1.2	2.0	-0.8	.80 -1.2	V
V_{OL} Output voltage Low V_{OH} High (82S231)	$I_{OUT} = 16\text{mA}$ $\overline{CE} = \text{Low}$, $I_{OUT} = -2\text{mA}$, High stored	2.4		0.45	2.4		0.5	V
I_{IL} Input current Low I_{IH} High	$V_{IN} = 0.45\text{V}$ $V_{IN} = 5.5\text{V}$			-100 40		-150	50	μA
I_{OLK} Output current Leakage (82S230) $I_{O(OFF)}$ Hi-Z state (82S231)	$\overline{CE} = \text{High}$, $V_{OUT} = 5.5\text{V}$ $\overline{CE} = \text{High}$, $V_{OUT} = 0.5\text{V}$ $\overline{CE} = \text{High}$, $V_{OUT} = 5.5\text{V}$			40 -40 40			60 -60 60	μA μA
I_{OS} Short circuit (82S231)	$V_{OUT} = 0\text{V}$	-20		-70	-15		-85	mA
I_{CC} V_{CC} supply current			120	140		120	140	mA
C_{IN} Capacitance Input C_{OUT} Output	$V_{CC} = 5.0\text{V}$ $V_{IN} = 2.0\text{V}$ $V_{OUT} = 2.0\text{V}$		5 8			5 8		pF

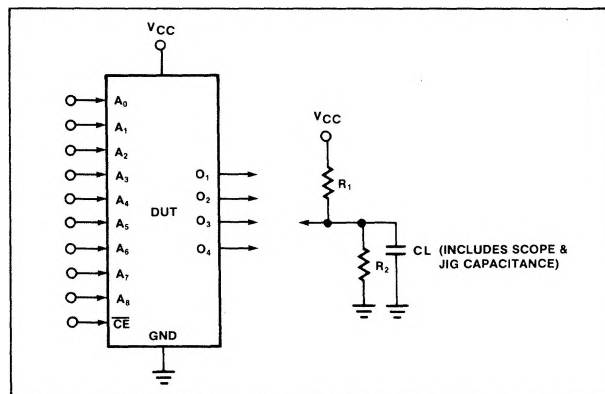
AC ELECTRICAL CHARACTERISTICS $R_1 = 270\Omega$, $R_2 = 600\Omega$, $C_L = 30\text{pF}$ ¹
 N82S230/231: $0^{\circ}\text{C} \leq T_A \leq +75^{\circ}\text{C}$, $4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$
 S82S230/231: $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$

PARAMETER	TO	FROM	N82S230/231			S82S230/231			UNIT
			Min	Typ ²	Max	Min	Typ ²	Max	
T_{AA} Access time T_{CE}	Output Output	Address Chip enable		40 20	50 30		40 20	70 35	ns
T_{CD} Disable time	Output	Chip disable		20	30		20	35	ns

NOTES

1. Positive current is defined as into the terminal referenced.
2. Typical values are at $V_{CC} = 5.0\text{V}$, $T_A = +25^{\circ}\text{C}$.

TEST LOAD CIRCUIT



VOLTAGE WAVEFORM

